## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re United States Patent Application of:		Docket No.:	2771-594-CIP
Applicants:	WANG, Ziyun, et al.	) Conf. No.:	1841
Application No.: Date Filed:	10/699,079 October 31, 2003	) Art Unit: ) Examiner:	1621 Samuel A. Barts
Title:	COMPOSITION AND METHOD FOR LOW TEMPERATURE DEPOSITION OF SILICON- CONTAINING FILMS	) Customer No.: ) ) ) ) ) ) ) ) ) ) ) )	23448

## **CERTIFICATE OF EFS FILING**

I hereby certify that this document is being filed via EFS in the United States Patent and Trademark Office on **June 7**, **2008**. /Steven J. Hultquist/

## RESPONSE TO APRIL 18, 2008 OFFICE ACTION AND FILING OF REQUEST FOR EXAMINATION UNDER 37 CFR 1.114 IN U.S. PATENT APPLICATION NO. 10/699,079

Mail Stop AF Commissioner for Patents P.O. Box 1450 Alexandria, Virginia 22313-1450

Sir:

This responds to the April 18, 2008 Office Action in the above-identified application. In view of the finality of the Office Action, a Request for Continued Examination is concurrently being filed with this response, to ensure substantive consideration of the amendments made herein.

Please amend the claims of the above-identified patent application as set out in **Section I** (Amendments to the Claims) hereof.

Remarks concerning the amendments to the claims and the substance of the April 18, 2008 Office Action are set out in **Section II** (**Remarks**) hereof.